Form PTO 1449 (ModiSed)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO.		SERIAL NO.			
(modified)			248442US0	NEW APPLICATION					
				APPLICANT					
LIST OF REFERENCES CITED BY APPLICANT				Toshiya SAGISAKA, et al.					
				FILING DATE	GROUP				
				HEREWITH					
				U.S. PATENT DOCUMENTS					
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS			
- PX	AA	6,492,079	12/10/02	SHIMADA, ET AL.	\				
	AB	6,596,449	07/22/03	SHIMADA, ET AL.					
	AC	4,892,949	01/09/90	SASAKI	_				
	AD	4,859,556	08/22/89	SASAKI				···	
	AE	5,840,454	11/24/98	NAGAI, ET AL.					
	AF	6,018,014	01/25/00	NAGAI, ET AL.					
	AG	6,187,494	02/13/01	KAWAMURA, ET AL.	<u> </u>				
TX.	AH	6,303,736	10/16/01	KAWAMURA, ET AL.				······	
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		DOCUMENT NUMBER	DATE	COUNTRY		TRANSLATION		·	
M	AJ	10-310635	11/24/98	JAPAN / w abstract		YES	<u> </u>	NO	
10	AK	08-157575	06/18/96	JAPAN / w abstract					
	AL	08-228034	09/03/96	JAPAN / w abstract					
	AM	08/228035	09/03/96			ļ			
				JAPAN / w abstract					
	AN	11-195790	07/21/99	JAPAN / w abstract					
	AO	58-198425	11/18/83	JAPAN / w abstract					
	AP	58-198043	11/17/83	JAPAN / w abstract	·····	· · · · · · · · · · · · · · · · · · ·			
100	AQ	60-098437	06/01/85	JAPAN / w abstract		,			
100	AR	WO97/09394	03/13/97	WIPO					
	AS								
	AT								
	AU	<u> </u>				<u> </u>			
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M	AY	Zhenan Bao, et al, Soluble and processable regioregular poly (3-hexylthiophene) for thin filed-efect transistor applications with high					Additional References sheet(s) attached		
<u> </u>		mobility. American Ins	titute of Physi	Addiss, pp., 4108-4110, 1996.		wonal References sheet(s) attached			
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*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.									

Form PTO 1449		U.S. DEPARTMENT OF COMMERCE	ATTY DOCKET NO.	SERIAL NO.				
(Modified)	PATENT AND TRADEMARK OFFICE		248442US0					
			APPLICANT					
LIST OF	REFER	RENCES CITED BY APPLICANT	Toshiya SAGISAKA, et al					
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·	LAA							
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	AAN							
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